

朝貴電子股份有限公司 CKM ELECTRONICS CO., LTD.

PRODUCT SPECIFICATION

CKM PN: 2541XX-XX

2.54mm PITCH CONNECTOR

REVISION HISTORY:

REV	REVISION DESCRIPTION	DATE	CREATED/REVISED
А	NEW RELEASE	2006.04.03	
В	UPGRADE THE FORM	2013.10.20	Qinggang yang

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PS-2541-001		Qinggang yang	Sun Lee	Angus Chen



1.0. SCOPE

This product specification covers performance, tests and quality requirements for **2541** Connector System When tests are performed on subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable product drawing.

2.0. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of the specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. APPLICABLE DOCUMENTS AND SPECIFICATIONS

EIA-364

UL-94 Flammability

3.0.REQUIREMENTS

- 3.1Design and Construction
 - Product shall be of the design, construction and physical dimensions specified on the applicable product drawing
- 3.2 MATERIAL

Materials used in the construction of this product shall be as specified on the applicable product drawing 3.3 Ratings

- 1. Voltage: 250 volts AC.
- 2. Current: See Figure 4 for applicable current carrying capability. Maximum rated current that can be carried by this product is limited by maximum operating temperature of the housings (85°C) and temperature rise of the housings (30°C). Variables to be considered for each application are: wire size, connector size, contact material, ambient temperature, and printed circuit board design.
- 3. Temperature: -25 to 85°C
- 3.4 Performance and Test Description.

Product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

3.5 Test Requirements and Procedures Summary

Test Description	Requirement	Procedure
Initial examination of product.	Meets requirements of product drawing and Application	EIA-364-18.Visual and dimensional (C of C)inspection per product drawing

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Final exami of produ	ination uct.	Meets visual requirements.			EIA-364-18.Visual inspection.		
ELECTRICAL							
Low Level 10 milliohm Contact initial.20 millio Resistance fin (LLCR).		ns maximum bhms maximum nal.	EIA-364-23.Subject specimens 100milliamperes maximum and 20m maximum open circuit voltage. See F		nens to I 20millivolts See Figure 3.		
1000 meg o Insulation initial.500 resistance. minim		hms minimum meg ohms um final.		EIA-364-21.500 volts DC, 2 minute hold. Test between adjacent contacts.			
Withstanding voltage.		One minute hold with no breakdown or flashover. 1.3milliamperes maximum leakage current.		EIA-364-20, Condition I.800 volts AC at sea level. Test between adjacent contacts.			
Temperature rise vs current.		30°C maximum temperature rise at specified current.		EIA-364-70, Method 1.Stabilize at a single current level until 3 readings at 5 minute intervals are within 1°C.See Figure 4.		e at a single at 5 minute Figure 4.	
MECHANICAL							
Solderability dip test. minimum of 95% so		shall have a older coverage.					
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Random vibration.	No discontinuities of 1 microsecond or longer duration. See Note	EIA-364-28, Test Condition VII, Condition Letter D. Subject mated specimens to 3.10 G's rms between 20 to 500 Hz.			
Mechanical shock.	No discontinuities of 1 microsecond or longer duration. See Note.	EIA-364-27, Method H. Subject mated specimens t 30 G's half-sine shock pulses of 11milliseconds duration. Three shocks in each direction applied alor 3mutually perpendicular planes, 18total shocks.			
Durability.	See Note.	EIA-364-9.Manually mate and un mate specimens with companion headers for 15 cycles at a maximum rate of500 cycles per hour.			
Mating force.	5 N maximum per contact.	EIA-364-13.Measure force necessary to mate specimens with companion headers a distance of 5.08 mm from point of initial contact at a maximum rate of12.7 mm per minute.			
Un mating force.	0.8 N minimum per contact.	EIA-364-13.Measure force necessary to un mate specimens from companion headers at a maximum rate of 12.7mm per minute			
Crimp tensile.	1.0kg minimum	EIA-364-8.Determine crimp tensile at a rate of25.4 mm per minute.			
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EIA-364-29. Apply axial load at a rate of 4.4 N per 1.0kg minimum Contact retention. second and hold for 6 seconds. **ENVIRONMENTAL** EIA-364-32, Test Condition VII. Subject mated specimens to 10 cycles between -55 and 105°C Thermal shock. See Note. with30 minute dwells at temperature extremes and 1 minute transition between temperatures EIA-364-31, Method III. Subject specimens Humidity/temperate See Note. to 10 cycles (10days) between 25 and 65°C at 80 cycling. to100% RH. EIA-364-17, Method A, Test Condition 4, Test Temperature life. See Note. Time Condition C. Subject mated specimens to 105°Cfor 500 hours NOTE Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Regualification Test Sequence shown in Figure2. Figure 1(End) Test Group (a) Test or Examination 2 3 4 1 5 Test Sequence (b) Initial examination of product 1 1 1 1 1 LLCR 3.7 2.6 Insulation resistance 2.5 Withstanding voltage 3.6 Temperature rise vs current 3 Solder ability dip test 2 Random vibration 5 Mechanical shock 6 Durability 4 Mating force 2 Un mating force 8 Crimp tensile 2 Contact retention 7 Thermal shock 4 Humidity/temperature cycling 4(C) Temperature life 5 Final examination of product 7 9 8 3 3 NOTE: **REVISION:** TITLE: **ECR/ECN INFORMATION:** SHEET No. EC No.: 2.54mm PITCH CONNECTOR В 5 of 7 DATE: 2009/09/22 DOCUMENT NUMBER: CREATED/REVISED CHECKED BY **APPROVED BY PS-2541-001** Angus Chen Qinggang yang Sun Lee



